Workshop on "Novel Development of Magnetic Microscopy and Smart Spintronics Materials"

Eki-Mae Campus, Osaka Electro-Communication University, Osaka, Japan,

January 17th and 18th, 2012

Sponsored: Japan Science and Technology Agency (JST) projects
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The Magnetics Society of Japan

Program

1. 17th January (Tuesday) 13:00-17:40

(1) Opening Address 13:00-13:05

(2) E. Bauer (Arizona State Univ., USA) 13:05-13:55
   “Ferromagnetic nanostructures on ZnS(100)”

(3) J. Kirschner (Max-Planck-Institute Halle, Germany) 13:55-14:45
   “Highly efficient multichannel spin-polarization detection”
   ~Break 14:45-15:10~

(4) T. Koshikawa (Osaka Electro-Communication Univ., Japan) 15:10-16:00
   “Dynamic observation of spintronics thin film materials with high brightness and
   high spin-polarized SPLEEM”
2. 18th January (Wednesday)  10:00-16:50

(1) W. Wulfhekel (Karlsruhe Institute of Technology, Germany)  10:00-10:50
   “From quantum spins to molecular spintronics”

(2) K. Koike (Hokkaido Univ., Japan)  10:50-11:40
   “Recent Progress in Spin-SEM”

~Lunch (11:40-13:10)~

(3) M.S. Altman (Hong Kong Univ. of Sci. and Technol., China)  13:10-14:00
   “SPLEEM investigations of Fe/W(111) films”

(4) A.K. Schmid (Lawrence Berkeley National Laboratory, USA)  14:00-14:50
   “Imaging Effects of Confinement and Proximity In-Situ by Spin-Polarized Low-Energy Electron Microscopy”

~Break (14:50-15:10)~

(5) B.N. Dev (Indian Association for the Cultivation of Science, India)  15:10-16:00
   “Magnetic domains in thin Co films on Si with a buffer layer: A spin polarized low energy electron microscopy investigation”

(6) K. Umezawa (Osaka Pref. Univ., Japan)  16:00-16:50
   “Low energy atom scattering spectroscopy for the analysis of insulator surfaces”